TrenchMOS ${ }^{\text {TM }}$ transistor

## GENERAL DESCRIPTION

N -channel enhancement mode logic level field-effect power transistor in a plastic envelope suitable for surface mounting. Using 'trench' technology the device features very low on-state resistance. It is intended for use in automotive and general purpose switching applications.

PINNING - SOT404

| PIN | DESCRIPTION |
| :---: | :--- |
| 1 | gate |
| 2 | drain (no connection <br> possible) |
| 3 | source |
| mb | drain |

## QUICK REFERENCE DATA

| SYMBOL | PARAMETER | MAX. | UNIT |
| :---: | :---: | :---: | :---: |
| $V_{\text {DS }}$ | Drain-source voltage | 55 | V |
| $\mathrm{I}_{\mathrm{D}}$ | Drain current (DC) | 75 | A |
| $\mathrm{P}_{\text {tot }}$ | Total power dissipation | 230 | W |
| $\mathrm{T}_{\mathrm{j}}$ | Junction temperature | 175 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{R}_{\mathrm{DS}(\mathrm{ON})}$ | Drain-source on-state resistance $\quad \mathrm{V}_{\mathrm{GS}}=5 \mathrm{~V}$ | 6.3 | $\mathrm{m} \Omega$ |
|  | $\mathrm{V}_{\mathrm{GS}}=10 \mathrm{~V}$ | 5.8 | $\mathrm{m} \Omega$ |

PIN CONFIGURATION
SYMBOL


## LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

| SYMBOL | PARAMETER | CONDITIONS | MIN. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {DS }}$ | Drain-source voltage |  |  | 55 | V |
| $V_{\text {dGa }}$ | Drain-gate voltage | $\mathrm{R}_{\mathrm{GS}}=20 \mathrm{k} \Omega$ |  | 55 | V |
| $\pm \mathrm{V}_{\text {GS }}$ | Gate-source voltage |  |  | 10 | V |
| $\pm \mathrm{V}_{\text {GSM }}$ | Non-repetitive gate-source voltage | $\mathrm{t}_{\mathrm{p}} \leq 50 \mu \mathrm{~S}$ | - | 15 | V |
| $\mathrm{I}_{\mathrm{D}}$ | Drain current (DC) | $\mathrm{T}_{\mathrm{mb}}=25^{\circ} \mathrm{C}$ | - | 75 | A |
| $\mathrm{I}_{\mathrm{D}}$ | Drain current (DC) | $\mathrm{T}_{\mathrm{mb}}=100{ }^{\circ} \mathrm{C}$ | - | 75 | A |
| $\mathrm{I}_{\mathrm{D}}$ | Drain current (pulse peak value) | $\mathrm{T}_{\mathrm{mb}}=25^{\circ} \mathrm{C}$ |  | 240 | A |
| $\mathrm{P}_{\text {tot }}$ | Total power dissipation | $\mathrm{T}_{\mathrm{mb}}=25^{\circ} \mathrm{C}$ | - | 230 | W |
| $\mathrm{T}_{\text {stg }}, \mathrm{T}_{\mathrm{j}}$ | Storage \& operating temperature |  | -55 | 175 | C |

## THERMAL RESISTANCES

| SYMBOL | PARAMETER | CONDITIONS | TYP. | MAX. | UNIT |
| :--- | :--- | :--- | :---: | :---: | :---: |
| $R_{\mathrm{th} j-m b}$ | Thermal resistance junction to <br> $R_{\mathrm{th} j-\mathrm{a}}$ | mounting base <br> Thermal resistance junction to <br> ambient | Minimum footprint, FR4 <br> board | 50 | 0.65 |

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## STATIC CHARACTERISTICS

$\mathrm{T}_{\mathrm{j}}=25^{\circ} \mathrm{C}$ unless otherwise specified

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {(BR)DSS }}$ | Drain-source breakdown voltage | $\mathrm{V}_{G S}=0 \mathrm{~V} ; \mathrm{I}_{\mathrm{D}}=0.25 \mathrm{~mA} ; \mathrm{T}_{\mathrm{i}}=-55^{\circ} \mathrm{C}$ | 55 50 | - | - | V |
| $\mathrm{V}_{\mathrm{GS} \text { (TO) }}$ | Gate threshold voltage | $V_{D S}=V_{G S} ; \mathrm{I}_{\mathrm{D}}=1 \mathrm{~mA}$ | 1 | 1.5 | 2.0 | V |
|  |  |  | 0.5 | - | 2.3 | V |
| $\mathrm{I}_{\text {DSS }}$ | Zero gate voltage drain current | $\mathrm{V}_{\mathrm{DS}}=55 \mathrm{~V} ; \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}$; | - | 0.05 | 10 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{V}^{\text {a }}$, $\mathrm{T}_{\mathrm{j}}=175^{\circ} \mathrm{C}$ | - | - | 500 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\mathrm{GSS}}$ <br> $\mathrm{R}_{\mathrm{DS}(\mathrm{ON})}$ | Gate source leakage current Drain-source on-state resistance | $\mathrm{V}_{\mathrm{GS}}= \pm 10 \mathrm{~V} ; \mathrm{V}_{\text {DS }}=0 \mathrm{~V}$ V GS | - | 2 5.3 | 100 6.3 | nA |
|  |  | $\mathrm{V}_{\mathrm{GS}}=5 \mathrm{~V} ; \mathrm{l}_{\mathrm{D}}=25 \mathrm{~A} \quad \mathrm{~T}_{\mathrm{j}}=175^{\circ} \mathrm{C}$ | - | 5.3 | 6.3 13.2 | $\mathrm{m} \Omega$ $\mathrm{m} \Omega$ |
|  |  | $\mathrm{V}_{\mathrm{GS}}=10 \mathrm{~V} ; \mathrm{I}_{\mathrm{D}}=25 \mathrm{~A}$ | - | 4.8 | 5.8 | $\mathrm{m} \Omega$ |
|  |  | $\mathrm{V}_{\mathrm{GS}}=4.5 \mathrm{~V} ; \mathrm{I}_{\mathrm{D}}=25 \mathrm{~A}$ | - | - | 6.7 | $\mathrm{m} \Omega$ |

## DYNAMIC CHARACTERISTICS

$\mathrm{T}_{\mathrm{mb}}=25^{\circ} \mathrm{C}$ unless otherwise specified

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :--- | :--- | :--- | :---: | :---: | :---: | :---: |
| $\mathrm{C}_{\text {iss }}$ | Input capacitance | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V} ; \mathrm{V}_{\mathrm{DS}}=25 \mathrm{~V} ; \mathrm{f}=1 \mathrm{MHz}$ | - | 6500 | 8600 | pF |
| $\mathrm{C}_{\text {oss }}$ | Output capacitance |  | - | 1000 | 1200 | pF |
| $\mathrm{C}_{\mathrm{rss}}$ | Feedback capacitance |  | - | 650 | 850 | pF |
| $\mathrm{t}_{\mathrm{d}}$ | Turn-on delay time | $\mathrm{V}_{\mathrm{DD}}=30 \mathrm{~V} ; \mathrm{R}_{\text {load }}=1.2 \Omega ;$ | - | 45 | 65 | ns |
| $\mathrm{t}_{\mathrm{r}}$ | Turn-on rise time | $\mathrm{V}_{\mathrm{GS}}=5 \mathrm{~V} ; \mathrm{R}_{\mathrm{G}}=10 \Omega$ | - | 180 | 270 | ns |
| $\mathrm{t}_{\mathrm{d} \text { off }}$ | Turn-off delay time |  | - | 420 | 590 | ns |
| $\mathrm{t}_{\mathrm{f}}$ | Turn-off fall time |  | - | 235 | 330 | ns |
| $\mathrm{~L}_{\mathrm{d}}$ | Internal drain inductance | Measured from upper edge of drain | - | 2.5 | - | nH |
| $\mathrm{L}_{\mathrm{s}}$ | Internal source inductance | tab to centre of die | Measured from source lead | - | 7.5 | - |
|  | soldering point to source bond pad |  | nH |  |  |  |

REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS
$\mathrm{T}_{\mathrm{j}}=25^{\circ} \mathrm{C}$ unless otherwise specified

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :--- | :--- | :--- | :---: | :---: | :---: | :---: |
| $\mathrm{I}_{\mathrm{DR}}$ | Continuous reverse drain |  | - | - | 75 | A |
|  | current |  | - | - | 240 | A |
| $\mathrm{I}_{\mathrm{DRM}}$ | Pulsed reverse drain current |  | - | 0.85 | 1.2 | V |
| $\mathrm{~V}_{\mathrm{SD}}$ | Diode forward voltage | $\mathrm{I}_{\mathrm{F}}=25 \mathrm{~A} ; \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}$ | - | 1.1 | - | V |
|  |  | $\mathrm{I}_{\mathrm{F}}=75 \mathrm{~A} ; \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}$ | - | 80 | - | ns |
| $\mathrm{t}_{\mathrm{rr}}$ | Reverse recovery time | $\mathrm{I}_{\mathrm{F}}=75 \mathrm{~A} ;-\mathrm{dl} \mathrm{I}_{\mathrm{F}} / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s} ;$ | - | 0.2 | - | $\mu \mathrm{C}$ |

AVALANCHE LIMITING VALUE

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :--- | :--- | :--- | :---: | :---: | :---: | :---: |
| $W_{\text {DSS }}$ | Drain-source non-repetitive <br> unclamped inductive turn-off <br> energy | $\mathrm{I}_{\mathrm{D}}=75 \mathrm{~A} ; \mathrm{V}_{\mathrm{DD}} \leq 25 \mathrm{~V} ;$ <br> $\mathrm{V}_{\mathrm{GS}}=5 \mathrm{~V} ; \mathrm{R}_{\mathrm{GS}}=50 \Omega ; \mathrm{T}_{\mathrm{mb}}=25{ }^{\circ} \mathrm{C}$ | - | - | 500 | mJ |

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Fig. 1. Normalised power dissipation. $P D \%=100 \cdot P_{D} / P_{D 25}{ }^{\circ} C=f\left(T_{m b}\right)$


Fig.2. Normalised continuous drain current. $I D \%=100 \cdot I_{D} / I_{D 25}{ }^{\circ}=f\left(T_{m b}\right)$; conditions: $V_{G S} \geq 5 \mathrm{~V}$


Fig.3. Safe operating area. $T_{m b}=25^{\circ} \mathrm{C}$ $I_{D} \& I_{D M}=f\left(V_{D S}\right) ; I_{D M}$ single pulse; parameter $t_{p}$



Fig.5. Typical output characteristics, $T_{j}=25^{\circ} \mathrm{C}$. $I_{D}=f\left(V_{D S}\right) ;$ parameter $V_{G S}$


Fig.6. Typical on-state resistance, $T_{j}=25^{\circ} \mathrm{C}$. $R_{D S(O N)}=f\left(I_{D}\right) ;$ parameter $V_{G S}$

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Fig.7. Typical on-state resistance, $T_{j}=25^{\circ} \mathrm{C}$. $R_{D S(O N)}=f\left(V_{G S}\right)$; conditions: $I_{D}=25$ A;


Fig.8. Typical transfer characteristics. $I_{D}=f\left(V_{G S}\right)$; conditions: $V_{D S}=25 \mathrm{~V}$; parameter $T_{j}$


Fig.9. Typical transconductance, $T_{j}=25^{\circ} \mathrm{C}$. $g_{t s}=f\left(I_{D}\right)$; conditions: $V_{D S}=25 \mathrm{~V}$


Fig.10. Normalised drain-source on-state resistance. $a=R_{D S(O N)} / R_{D S(O N) 25{ }^{\circ} \mathrm{C}}=f\left(T_{j}\right) ; I_{D}=25 A ; V_{G S}=5 \mathrm{~V}$


Fig.11. Gate threshold voltage.
$V_{G S(T O)}=f\left(T_{j}\right) ;$ conditions: $I_{D}=1 \mathrm{~mA} ; V_{D S}=V_{G S}$


Fig.12. Sub-threshold drain current. $I_{D}=f\left(V_{G S}\right)$; conditions: $T_{j}=25^{\circ} \mathrm{C} ; V_{D S}=V_{G S}$

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Fig.13. Typical capacitances, $C_{i s s}, C_{\text {oss }}, C_{\text {rss }}$. $C=f\left(V_{D S}\right)$; conditions: $V_{G S}=0 V ; f=1 \mathrm{MHz}$


Fig.14. Typical turn-on gate-charge characteristics.
$V_{G S}=f\left(Q_{G}\right)$; conditions: $I_{D}=50$ A; parameter $V_{D S}$


Fig.15. Typical reverse diode current. $I_{F}=f\left(V_{S D S}\right)$; conditions: $V_{G S}=0 \mathrm{~V}$; parameter $T_{j}$


Fig.16. Normalised avalanche energy rating. $W_{D S S} \%=f\left(T_{m b}\right)$; conditions: $I_{D}=75 \mathrm{~A}$



Fig.18. Switching test circuit.

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## MECHANICAL DATA



Fig.19. SOT404 surface mounting package. Centre pin connected to mounting base.

## Notes

1. This product is supplied in anti-static packaging. The gate-source input must be protected against static discharge during transport or handling.
2. Refer to SMD Footprint Design and Soldering Guidelines, Data Handbook SC18.
3. Epoxy meets UL94 V0 at 1/8".

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Logic level FET

## MOUNTING INSTRUCTIONS



## DEFINITIONS

| Data sheet status |  |
| :--- | :--- |
| Objective specification | This data sheet contains target or goal specifications for product development. |
| Preliminary specification | This data sheet contains preliminary data; supplementary data may be published later. |
| Product specification | This data sheet contains final product specifications. |
| Limiting values |  |
| Limiting values are given in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one <br> or more of the limiting values may cause permanent damage to the device. These are stress ratings only and <br> operation of the device at these or at any other conditions above those given in the Characteristics sections of <br> this specification is not implied. Exposure to limiting values for extended periods may affect device reliability. |  |
| Application information |  |
| Where application information is given, it is advisory and does not form part of the specification. |  |
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## LIFE SUPPORT APPLICATIONS

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